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# PATENT ABSTRACTS OF JAPAN

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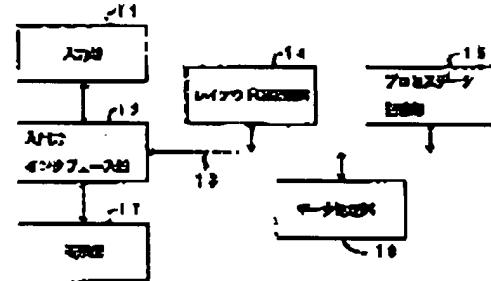
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## (54) METHOD AND APPARATUS FOR EVALUATING CIRCUIT

### (57)Abstract:

**PURPOSE:** To evaluate a circuit accurately based on the thermal energy generated from a circuit to be evaluated based on the structure at a specified part and the thermal energy generated based on the electromagnetic characteristics of the circuit.

**CONSTITUTION:** When an evaluation operation is commanded at an input section 11, a data processing section 16 reads in a layout diagram from a layout diagram memory section 14 and presents the layout diagram on a display section 17. An element to be simulated is then extracted while observing the displaying section 17. The processing section 16 then creates a concentrated constant circuit diagram for the part other than the circuit elements. On the other hand, the processing section 16 reads in data for every process of element part from a process data memory section 15 and creates the structural data for the element part. Subsequently, the processing section 16 determines the quantity of heat from the thermal energy at the element part and the concentrated constant element based on the voltage and current distributions of elements in the circuit diagram and a decision of GO/NO GO is made for the circuit by comparing the quantity of heat.



## LEGAL STATUS

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